

## NanoScope® II Scanning Probe Microscopes

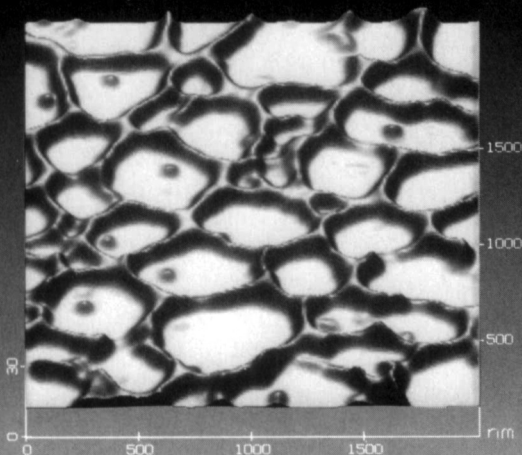


Image of a Web-like Voronoi Tessellation Pattern of a Polystyrene Coating on Silicon: Sample prepared by CIE, University of Minnesota, and scanned at Digital Instruments.

## AFM: Yet More Power

Digital Instruments is now shipping the NanoScope AFM (Atomic Force Microscope, an ultra-low force profilometer) as an add-on option for the Nanoscope II.

Features Include:

- Atomic Resolution
- Large scans up to  $75\mu \times 75\mu$
- Operation under liquid or in air  
(ref. Weisenhorn *et al*, Science, 16 Mar 90)
- No extra controllers needed

The NanoScope AFM is backed up by the experience Digital Instruments has gained in delivering over 300 STM (Scanning Tunneling Microscope) systems.

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